

Automotive-grade N-channel 600 V, 0.093 Ω , 29 A, MDmesh™ II Power MOSFET in a D²PAK package

Datasheet — production data

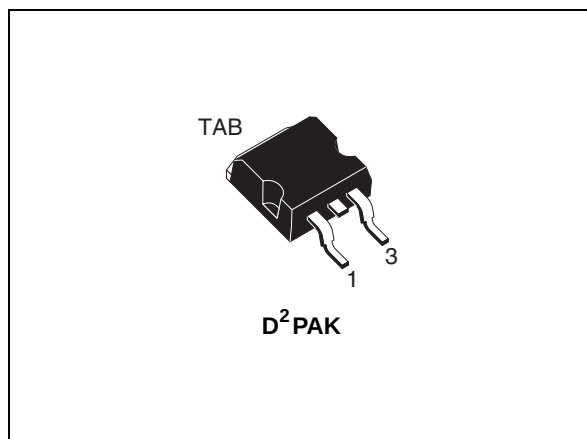
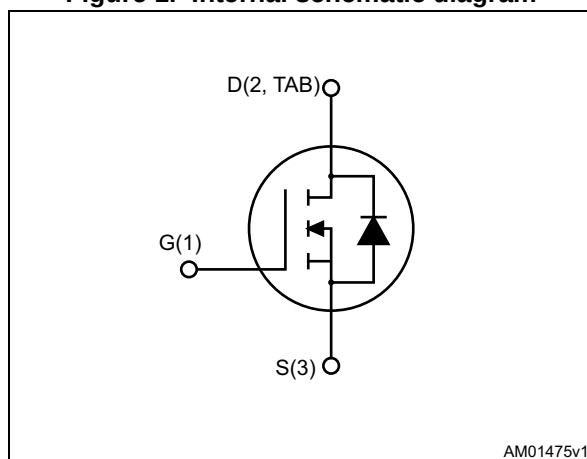


Figure 1. Internal schematic diagram



Features

Order code	V _{DS} @ T _{Jmax}	R _{DS(on)} max.	I _D	P _{TOT}
STB36NM60N	650 V	0.105 Ω	29 A	210 W

- Designed for automotive applications and AEC-Q101 qualified
- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance

Applications

- Switching applications

Description

This device is an N-channel Power MOSFET developed using the second generation of MDmesh™ technology. This revolutionary Power MOSFET associates a vertical structure to the company's strip layout to yield one of the world's lowest on-resistance and gate charge. It is therefore suitable for the most demanding high efficiency converters.

Table 1. Device summary

Order code	Marking	Packages	Packaging
STB36NM60N	36NM60N	D ² PAK	Tape and reel

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1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage	600	V
V_{GS}	Gate-source voltage	± 25	V
I_D	Drain current (continuous) at $T_C = 25\text{ }^{\circ}\text{C}$	29	A
I_D	Drain current (continuous) at $T_C = 100\text{ }^{\circ}\text{C}$	18	A
$I_{DM}^{(1)}$	Drain current (pulsed)	116	A
P_{TOT}	Total dissipation at $T_C = 25\text{ }^{\circ}\text{C}$	210	W
I_{AR}	Avalanche current, repetitive or not-repetitive (pulse width limited by T_j max.)	10.5	A
E_{AS}	Single pulse avalanche energy (Starting $T_j = 25\text{ }^{\circ}\text{C}$, $I_D = I_{AR}$, $V_{DD} = 50\text{ V.}$)	345	mJ
$dv/dt^{(2)}$	Peak diode recovery voltage slope	15	V/ns
T_{stg}	Storage temperature	-55 to 150	$^{\circ}\text{C}$
T_j	Max. operating junction temperature	150	$^{\circ}\text{C}$

1. Pulse width limited by safe operating area.
2. $I_{SD} \leq 29\text{ A}$, $di/dt \leq 400\text{ A}/\mu\text{s}$, $V_{DS\text{ peak}} \leq V_{(BR)DSS}$, $V_{DD} = 80\% V_{(BR)DSS}$

Table 3. Thermal data

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case max	0.6	$^{\circ}\text{C}/\text{W}$
$R_{thj-pcb}^{(1)}$	Thermal resistance junction-pcb max	30	$^{\circ}\text{C}/\text{W}$

1. When mounted on FR-4 board of 1inch², 2oz Cu, $t < 10\text{ sec}$

2 Electrical characteristics

(T_{case} = 25°C unless otherwise specified)

Table 4. On /off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	I _D = 1 mA, V _{GS} = 0	600			V
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V _{DS} = 600 V			10	μA
		V _{DS} = 600 V, T _C = 125 °C			100	μA
I _{GSS}	Gate-body leakage current (V _{DS} = 0)	V _{GS} = ± 25 V			±100	nA
V _{GS(th)}	Gate threshold voltage	V _{DS} = V _{GS} , I _D = 250 μA	2	3	4	V
R _{DS(on)}	Static drain-source on-resistance	V _{GS} = 10 V, I _D = 14.5 A		0.093	0.105	Ω

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V _{DS} = 100 V, f = 1 MHz, V _{GS} = 0	-	2722 173 1.75	-	pF pF pF
C _{oss eq.} ⁽¹⁾	Equivalent Output capacitance	V _{GS} = 0, V _{DS} = 0 to 480 V	-	458	-	pF
R _g	Gate input resistance	f = 1 MHz Gate DC Bias = 0 Test signal level = 20 mV open drain	-	2.9	-	Ω
Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	V _{DD} = 480 V, I _D = 29 A, V _{GS} = 10 V (see Figure 15)	-	83.6 14 45	-	nC nC nC

1. C_{oss eq.} is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DS}

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 300\text{ V}$, $I_D = 14.5\text{ A}$, $R_G = 4.7\ \Omega$, $V_{GS} = 10\text{ V}$ (see Figure 14)	-	17	-	ns
t_r	Rise time		-	34	-	ns
$t_{d(off)}$	Turn-off-delay time		-	106	-	ns
t_f	Fall time		-	67	-	ns

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min	Typ.	Max	Unit
I_{SD}	Source-drain current		-		29	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		116	A
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 29\text{ A}$, $V_{GS} = 0$	-		1.6	V
t_{rr}	Reverse recovery time	$I_{SD} = 29\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$ $V_{DD} = 60\text{ V}$ (see Figure 19)	-	408		ns
Q_{rr}	Reverse recovery charge		-	8		μC
I_{RRM}	Reverse recovery current		-	39		A
t_{rr}	Reverse recovery time	$I_{SD} = 29\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$ $V_{DD} = 60\text{ V}$ $T_j = 150\text{ }^\circ\text{C}$ (see Figure 19)	-	480		ns
Q_{rr}	Reverse recovery charge		-	10		μC
I_{RRM}	Reverse recovery current		-	42		A

1. Pulse width limited by safe operating area
2. Pulsed: pulse duration = 300 μs , duty cycle 1.5%

2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

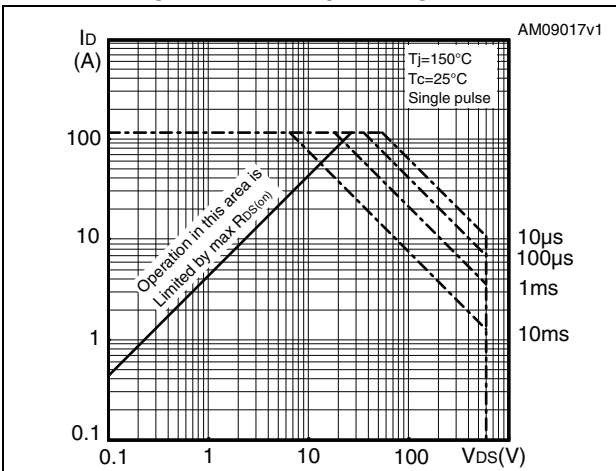


Figure 3. Thermal impedance

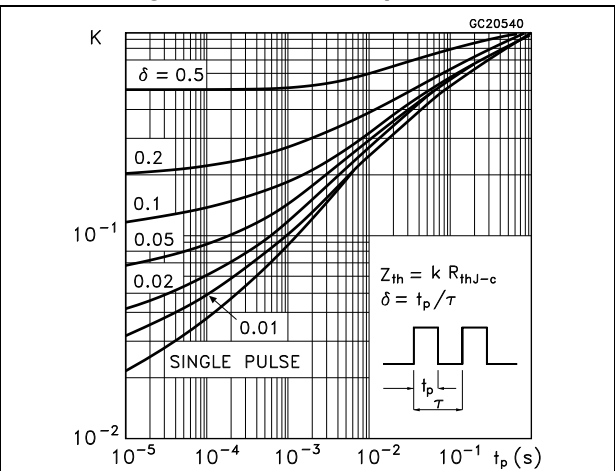


Figure 4. Output characteristics

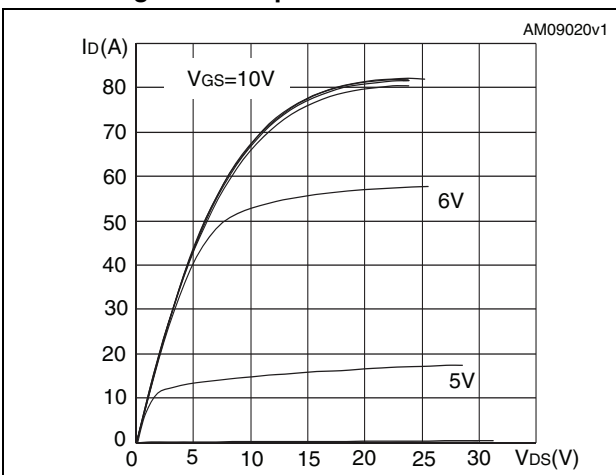


Figure 5. Transfer characteristics

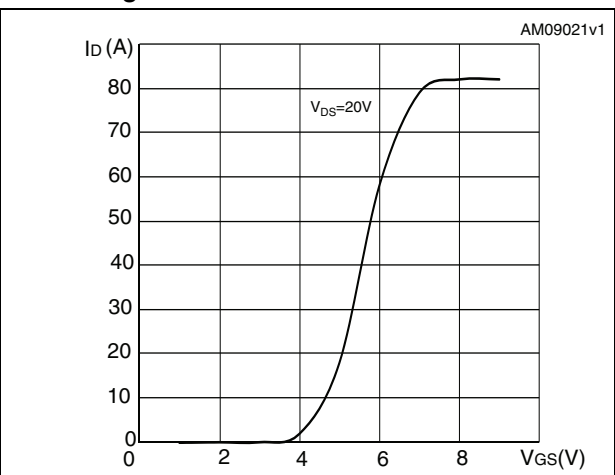


Figure 6. Gate charge vs gate-source voltage

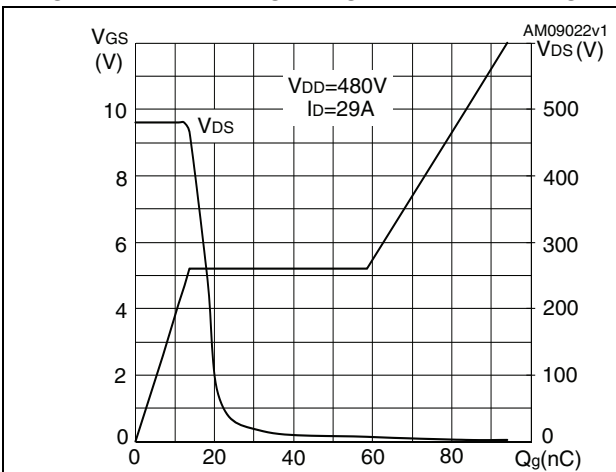


Figure 7. Static drain-source on-resistance

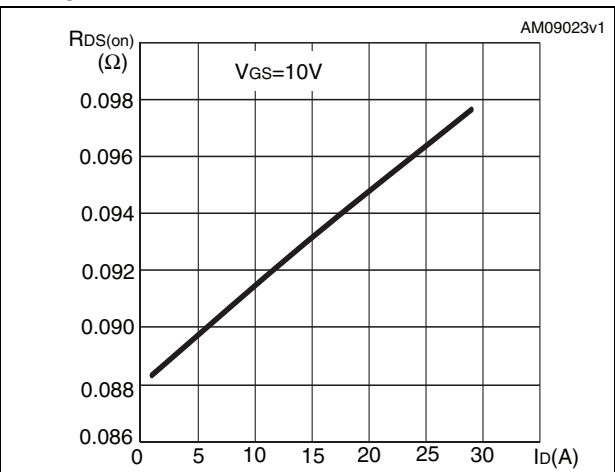


Figure 8. Capacitance variations

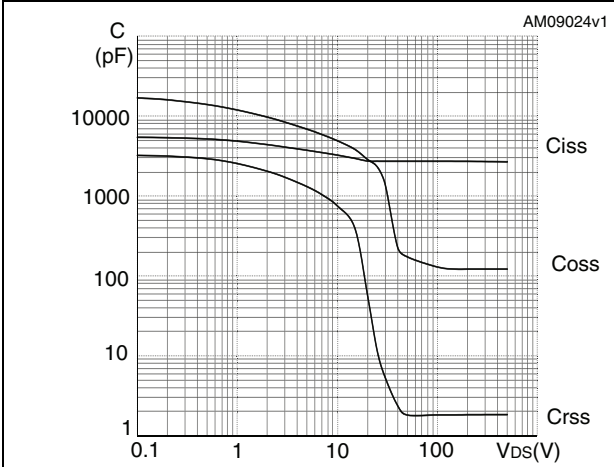


Figure 9. Output capacitance stored energy

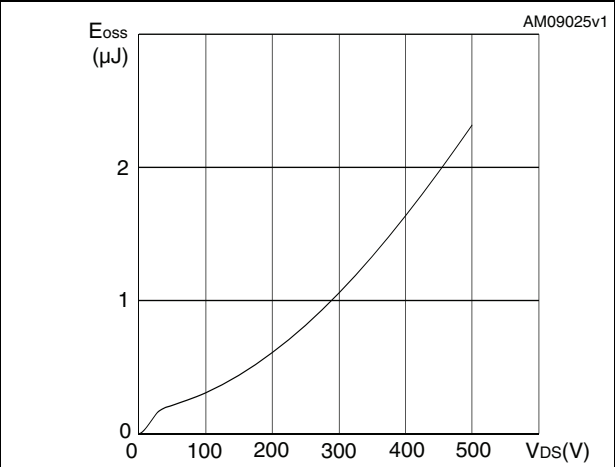


Figure 10. Normalized gate threshold voltage vs temperature

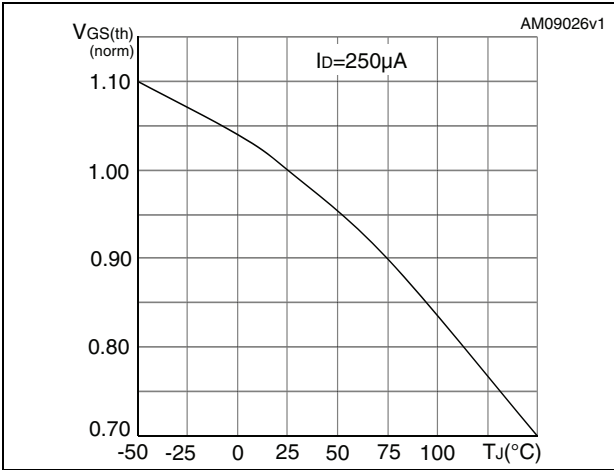


Figure 11. Normalized on-resistance vs temperature

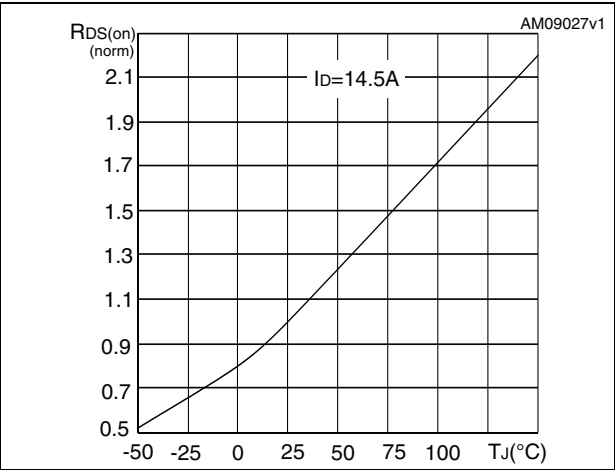


Figure 12. Normalized $V_{(BR)DSS}$ vs temperature

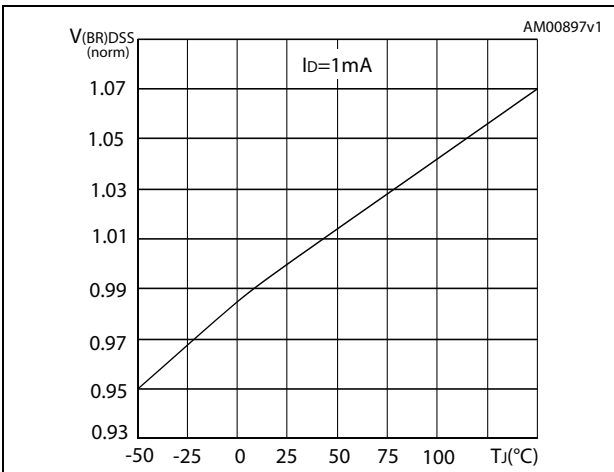
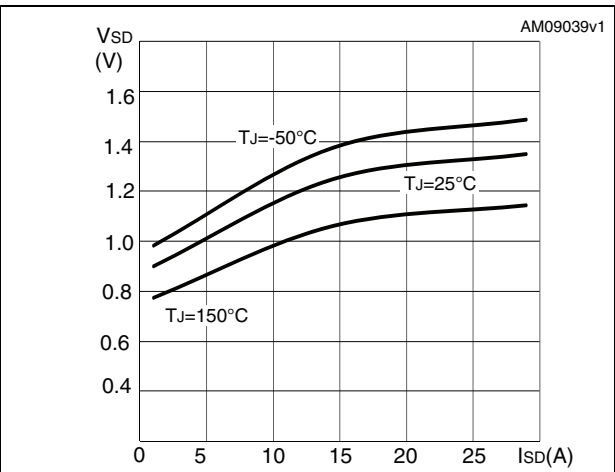


Figure 13. Source-drain diode forward characteristics



4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK® is an ST trademark.

Figure 20. D²PAK (TO-263) type A package outline

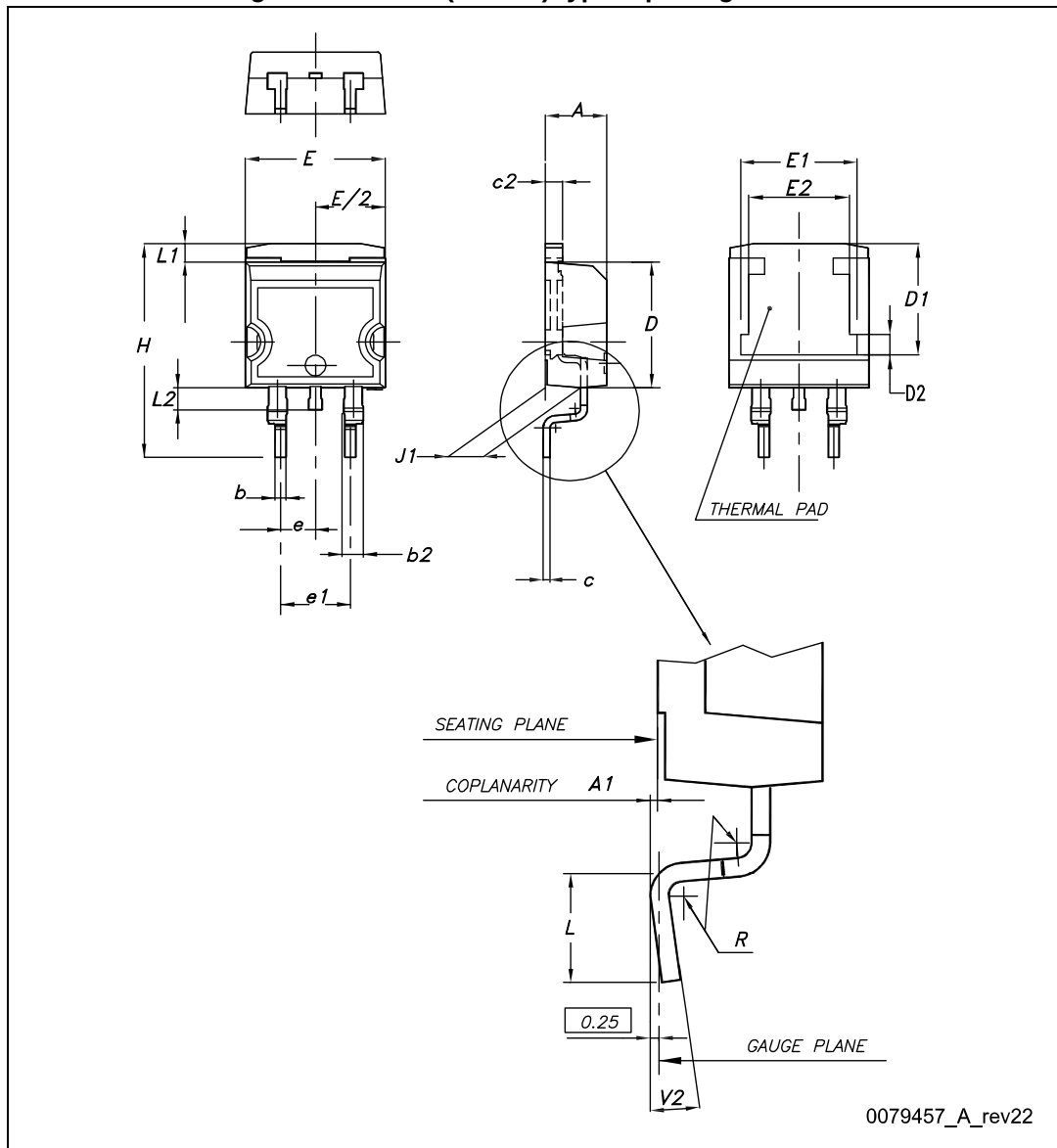
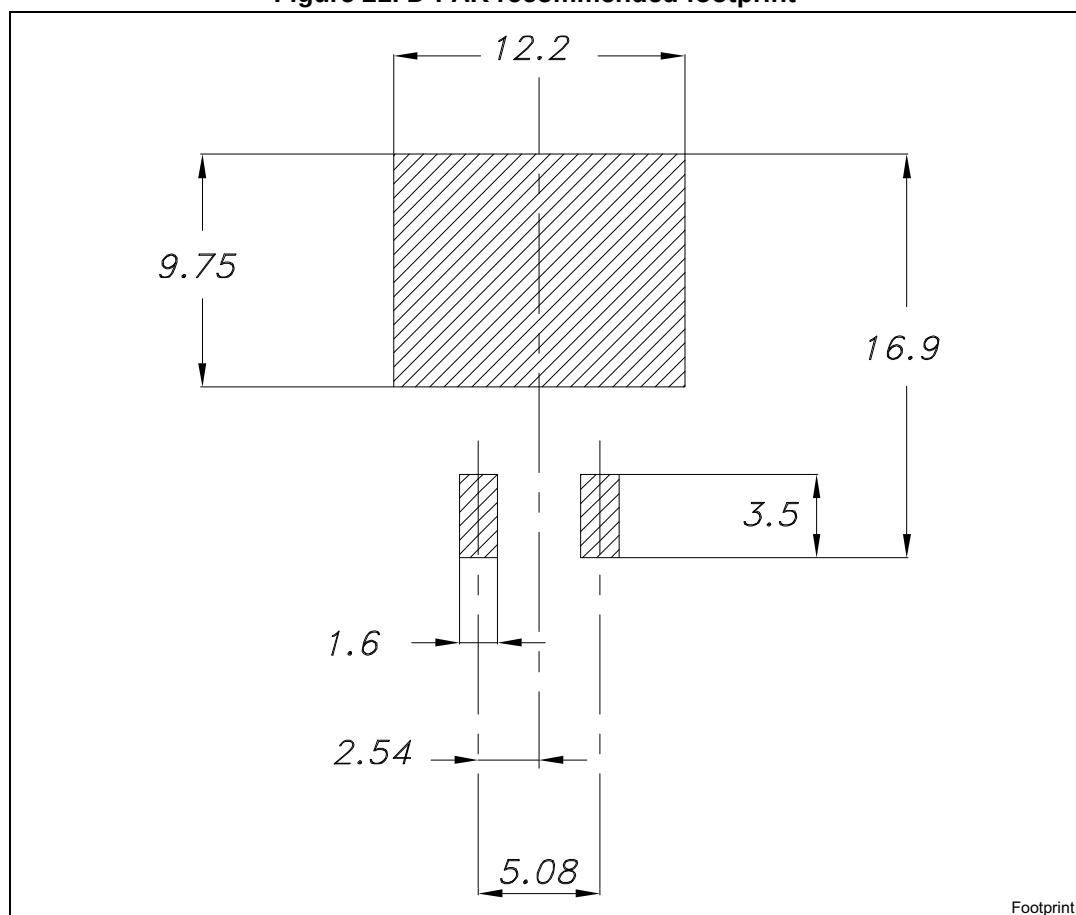


Table 8. D²PAK (TO-263) type A mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.40		4.60
A1	0.03		0.23
b	0.70		0.93
b2	1.14		1.70
c	0.45		0.60
c2	1.23		1.36
D	8.95		9.35
D1	7.50	7.75	8.00
D2	1.10	1.30	1.50
E	10		10.40
E1	8.50	8.70	8.90
E2	6.85	7.05	7.25
e		2.54	
e1	4.88		5.28
H	15		15.85
J1	2.49		2.69
L	2.29		2.79
L1	1.27		1.40
L2	1.30		1.75
R		0.4	
V2	0°		8°

Figure 21. D²PAK recommended footprint^(a)

a. All dimension are in millimeters

5 Packing information

Figure 22. Tape

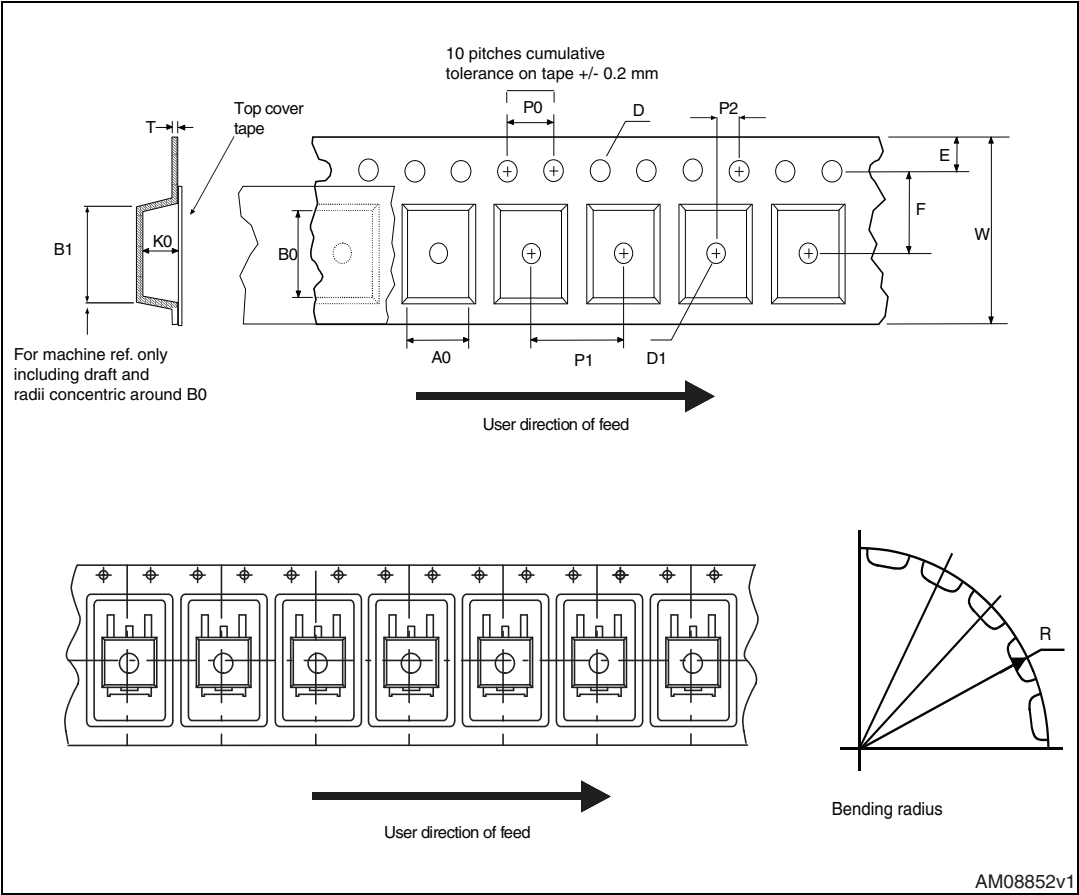


Diagram illustrating the dimensions of a reel, showing a cross-section and a side view.

Dimensions and Labels:

- A:** Overall diameter of the reel.
- B:** Diameter of the access hole.
- C:** Diameter of the tape slot in the core.
- D:** Diameter of the full radius.
- E:** Thickness of the tape.
- F:** Width of the tape.
- G:** Measured at the hub.
- H:** Thickness of the tape.
- I:** Width of the tape.
- J:** Thickness of the tape.
- K:** Width of the tape.
- L:** Thickness of the tape.
- M:** Width of the tape.
- N:** Thickness of the tape.
- O:** Width of the tape.
- P:** Thickness of the tape.
- Q:** Width of the tape.
- R:** Thickness of the tape.
- S:** Width of the tape.
- T:** Thickness of the tape.
- U:** Width of the tape.
- V:** Thickness of the tape.
- W:** Width of the tape.
- X:** Thickness of the tape.
- Y:** Width of the tape.
- Z:** Thickness of the tape.
- Access hole:** A hole in the reel for access.
- At slot location:** The location of the tape slot.
- Full radius:** The radius of the full reel.
- Tape slot in core for tape start 25 mm min. width:** The slot in the core for the tape to start, with a minimum width of 25 mm.

Tape			Reel		
Dim.	mm		Dim.	mm	
	Min.	Max.		Min.	Max.
A0	10.5	10.7	A		330
B0	15.7	15.9	B	1.5	
D	1.5	1.6	C	12.8	13.2
D1	1.59	1.61	D	20.2	
E	1.65	1.85	G	24.4	26.4
F	11.4	11.6	N	100	
K0	4.8	5.0	T		30.4
P0	3.9	4.1			
P1	11.9	12.1	Base qty		1000
P2	1.9	2.1	Bulk qty		1000
R	50				
T	0.25	0.35			
W	23.7	24.3			

6 Revision history

Table 10. Document revision history

Date	Revision	Changes
16-Nov-2009	1	First release.
22-Jun-2011	2	Document status promoted from preliminary data to datasheet.
10-May-2012	3	Figure 6: Gate charge vs gate-source voltage has been modified. Minor text changes.
19-Sep-2014	4	– Modified: title and features – Minor text changes
09-Jun-2015	5	– Updated title, internal schematic diagram and features in cover page. – Updated Table 3: Thermal data and Figure 12: Normalized $V_{(BR)DSS}$ vs temperature . – Updated Section 4: Package information . – Minor text changes.

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